## DABiC-IV, 32-BIT SERIAL-INPUT, LATCHED SOURCE DRIVER

The A6818- devices combine a 32-bit CMOS shift register, accompanying data latches and control circuitry with bipolar sourcing outputs and pnp active pull downs. Designed primarily to drive vacuumfluorescent displays, the 60 V and -40 mA output ratings also allow these devices to be used in many other peripheral power driver applications. The A6818- features an increased data input rate (compared with the older UCN/UCQ5818-F) and a controlled output slew rate. The CMOS shift register and latches allow direct interfacing with microprocessor-based systems. With a 3.3 V or 5 V logic supply, typical serial-data input rates are up to 33 MHz.

A CMOS serial data output permits cascade connections in applications requiring additional drive lines. Similar devices are available as the A6809- and A6810- (10 bits), A6811- (12 bits), and A6812- (20 bits).

The A6818- output source drivers are npn Darlingtons, capable of sourcing up to 40 mA. The controlled output slew rate reduces electromagnetic noise, which is an important consideration in systems that include telecommunications and/or microprocessors and to meet government emissions regulations. For inter-digit blanking, all output drivers can be disabled and all sink drivers turned on with a BLANK-ING input high. The pnp active pull-downs will sink at least 2.5 mA.

Three temperature ranges are available for optimum performance in commercial (suffix S-), industrial (suffix E-), or automotive (suffix K-) applications. Package styles are provided for through-hole DIP (suffix -A) or minimum-area surface-mount PLCC (suffix -EP). Copper lead frames, low logic-power dissipation, and low output-saturation voltages allow these devices to drive most multiplexed vacuum-fluorescent displays over the maximum operating temperature range.

## A6818xA SERIAL DATA OUT 38 OUT 1 37 OUT 2 36 OUT 3 35 OUT<sub>4</sub> 34 OUT<sub>5</sub> - 33 OUT 6 32 OUT<sub>7</sub> REGISTER REGISTER 31 OUT<sub>8</sub> 30 OUT<sub>9</sub> 29 OUT 10 27 OUT 12 26 OUT 13 25 OUT <sub>14</sub> 24 OUT 15 23 OUT 16 ST 22 STROBE BLANKING 19 GROUND 20 CLK 21 CLOCK

#### **ABSOLUTE MAXIMUM RATINGS** at $T_A = 25^{\circ}C$

Logic Supply Voltage, V <sub>DD</sub>
Continuous Output Current Range,
I <sub>OUT</sub> 40 mA to +15 mA
Input Voltage Range,
$V_{IN}$ 0.3 V to $V_{DD}$ + 0.3 V
Package Power Dissipation,
P <sub>D</sub> See Graph
Operating Temperature Range, T <sub>A</sub>
(Suffix 'E-')40°C to +85°C

Storage Temperature Range, T<sub>S</sub> ..... -55°C to +125°C

(Suffix 'K-') ..... -40°C to +125°C

(Suffix 'S-') ..... -20°C to +85°C

Caution: These CMOS devices have input static protection (Class 2) but are still susceptible to damage if exposed to extremely high static electrical charges.

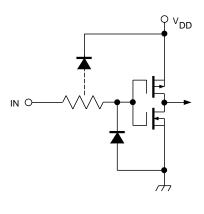
#### **FEATURES**

- High-Speed Data Storage
- 60 V Minimum
- Output Breakdown
- High Data Input Rate
- PNP Active Pull-Downs
- Controlled Output Slew Rate
  Low Output-Saturation Voltages
  - Low-Power CMOS Logic and Latches
  - Improved Replacements for SN75518N, SN75518NF, UCN5818-, and UCQ5818-

Complete part number includes a suffix to identify operating temperature range (E-, K-, or S-) and package type (-A or -EP). Always order by complete part number, e.g., A6818SEP.

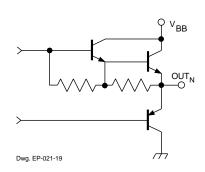


## TYPICAL INPUT CIRCUIT

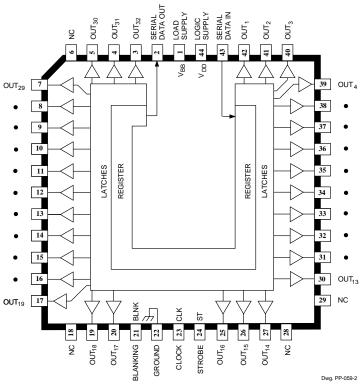


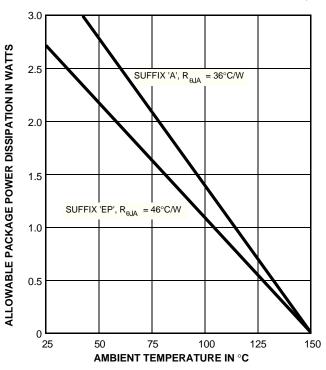
Dwg. EP-010-5

## **TYPICAL OUTPUT DRIVER**



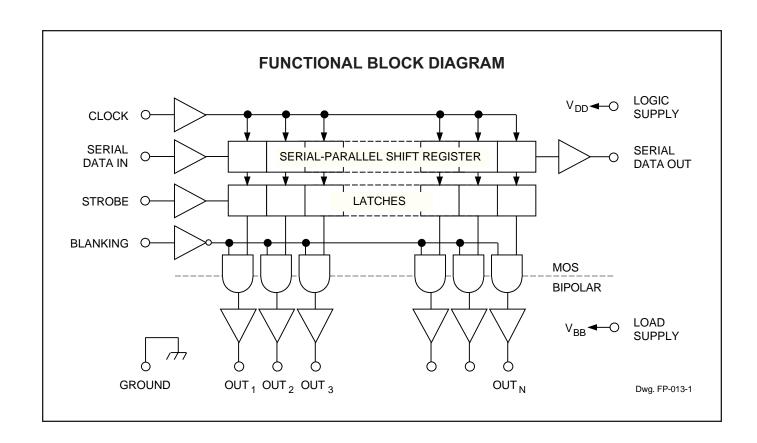
## A6818xEP





Dwg. GP-025A





#### **TRUTH TABLE**

Serial		Shift Register Contents				Serial	Latch Contents						Output Contents									
Data Input	Clock Input		l <sub>2</sub>	l <sub>3</sub>		I <sub>N-1</sub>	I <sub>N</sub>	Data Output	Strobe Input	I <sub>1</sub>	l <sub>2</sub>	I <sub>3</sub>		I <sub>N-1</sub>	I <sub>N</sub>	Blanking	I <sub>1</sub>	l <sub>2</sub>	I <sub>3</sub>		I <sub>N-1</sub>	I <sub>N</sub>
Н	7	Н	R <sub>1</sub>	$R_2$		R <sub>N-2</sub>	R <sub>N-1</sub>	R <sub>N-1</sub>														
L		L	R <sub>1</sub>	$R_2$		R <sub>N-2</sub>	R <sub>N-1</sub>	R <sub>N-1</sub>														
Х	l	$R_1$	$R_2$	$R_3$		R <sub>N-1</sub>	$R_N$	R <sub>N</sub>														
		Х	Χ	Χ		Χ	Χ	Х	L	$R_1$	$R_2$	$R_3$		R <sub>N-1</sub>	$R_N$							
		P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>		P <sub>N-1</sub>	P <sub>N</sub>	P <sub>N</sub>	Н	P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>		P <sub>N-1</sub>	P <sub>N</sub>	L	P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>		P <sub>N-1</sub>	$P_{N}$
										Χ	Χ	Χ		Χ	Χ	Н	L	L	L		L	L

L = Low Logic Level H = High Logic Level X = Irrelevant P = Present State R = Previous State

## 6818 32-BIT SERIAL-INPUT, LATCHED SOURCE DRIVER

# ELECTRICAL CHARACTERISTICS at $T_A$ = +25°C (A6818S-) or over operating temperature range (A6818E- and A6818K-), $V_{BB}$ = 60 V unless otherwise noted.

			Limits	@ V <sub>DD</sub> :	= 3.3 V	Limits			
Characteristic	Symbol	Test Conditions	MIn.	Тур.	Max.	Min.	Тур.	Max.	Units
Output Leakage Current	I <sub>CEX</sub>	V <sub>OUT</sub> = 0 V	_	<-0.1	-15	_	<-0.1	-15	μΑ
Output Voltage	V <sub>OUT(1)</sub>	I <sub>OUT</sub> = -25 mA	57.5	58.3	_	57.5	58.3	_	V
	V <sub>OUT(0)</sub>	I <sub>OUT</sub> = 1 mA	_	1.0	1.5	_	1.0	1.5	V
Output Pull-Down Current	I <sub>OUT(0)</sub>	V <sub>OUT</sub> = 5 V to V <sub>BB</sub>	2.5	5.0	_	2.5	5.0	_	mA
Input Voltage	V <sub>IN(1)</sub>		2.2	_	_	3.3	_	_	V
	V <sub>IN(0)</sub>		_	_	1.1	_	_	1.7	V
Input Current	I <sub>IN(1)</sub>	$V_{IN} = V_{DD}$	_	<0.01	1.0	_	<0.01	1.0	μА
	I <sub>IN(0)</sub>	V <sub>IN</sub> = 0.8 V	_	<-0.01	-1.0	_	<-0.01	-1.0	μΑ
Input Clamp Voltage	V <sub>IK</sub>	I <sub>IN</sub> = -200 μA	_	-0.8	-1.5	_	-0.8	-1.5	V
Serial Data Output Voltage	V <sub>OUT(1)</sub>	I <sub>OUT</sub> = -200 μA	2.8	3.05	_	4.5	4.75	_	V
	V <sub>OUT(0)</sub>	I <sub>OUT</sub> = 200 μA	_	0.15	0.3	_	0.15	0.3	V
Maximum Clock Frequency	f <sub>c</sub>		10	33	_	10	33	_	MHz
Logic Supply Current	I <sub>DD(1)</sub>	All Outputs High	_	0.25	0.75	_	0.3	1.0	mA
	I <sub>DD(0)</sub>	All Outputs Low	_	0.25	0.75	_	0.3	1.0	mA
Load Supply Current	I <sub>BB(1)</sub>	All Outputs High, No Load	_	4.5	9.0	_	4.5	9.0	mA
	I <sub>BB(0)</sub>	All Outputs Low	_	0.2	20	_	0.2	20	μΑ
Blanking-to-Output Delay	t <sub>dis(BQ)</sub>	C <sub>L</sub> = 30 pF, 50% to 50%	_	0.7	2.0	_	0.7	2.0	μs
	t <sub>en(BQ)</sub>	C <sub>L</sub> = 30 pF, 50% to 50%	_	1.8	3.0	_	1.8	3.0	μs
Strobe-to-Output Delay	t <sub>p(STH-QL)</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \leq 30 \text{ pF}$	_	0.7	2.0	_	0.7	2.0	μs
	t <sub>p(STH-QH)</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	_	1.8	3.0	_	1.8	3.0	μs
Output Fall Time	t <sub>f</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	2.4	_	12	2.4	_	12	μs
Output Rise Time	t <sub>r</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	2.4	_	12	2.4	_	12	μs
Output Slew Rate	dV/dt	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	4.0	_	20	4.0	_	20	V/μs
Clock-to-Serial Data Out Delay	t <sub>p(CH-SQX)</sub>	I <sub>OUT</sub> = ±200 μA	_	50	_	_	50	_	ns

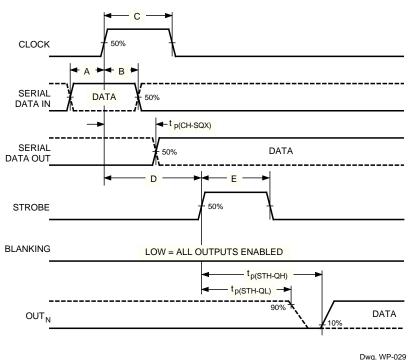
Negative current is defined as coming out of (sourcing) the specified device terminal.

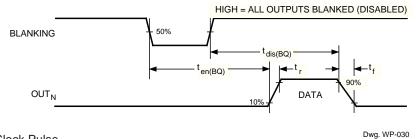


Typical data is is for design information only and is at  $T_A = +25$ °C.

## TIMING REQUIREMENTS and SPECIFICATIONS

(Logic Levels are V<sub>DD</sub> and Ground)





A. Data Active Time Before Clock Pulse
(Data Set-Up Time), t <sub>su(D)</sub> 25 ns
B. Data Active Time After Clock Pulse
(Data Hold Time), t <sub>h(D)</sub>
C. Clock Pulse Width, t <sub>w(CH)</sub> 50 ns
$\textbf{D.}$ Time Between Clock Activation and Strobe, $t_{su(C)}$ 100 $\textbf{ns}$
<b>E.</b> Strobe Pulse Width, $t_{w(STH)}$
NOTE – Timing is representative of a 10 MHz clock. Significantly higher speeds are attainable.

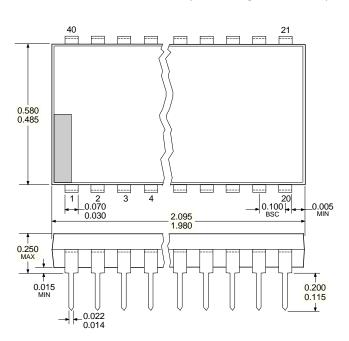
Serial Data present at the input is transferred to the shift register on the logic "0" to logic "1" transition of the CLOCK input pulse. On succeeding CLOCK pulses, the registers shift data information towards the SERIAL DATA OUTPUT. The SERIAL DATA must appear at the input prior to the rising edge of the CLOCK input waveform.

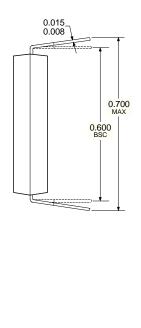
Information present at any register is transferred to the respective latch when the STROBE is high (serial-to-parallel conversion). The latches will continue to accept new data as long as the STROBE is held high. Applications where the latches are bypassed (STROBE tied high) will require that the BLANKING input be high during serial data entry.

When the BLANKING input is high, the output source drivers are disabled (OFF); the pnp active pull-down sink drivers are ON. The information stored in the latches is not affected by the BLANKING input. With the BLANKING input low, the outputs are controlled by the state of their respective latches.

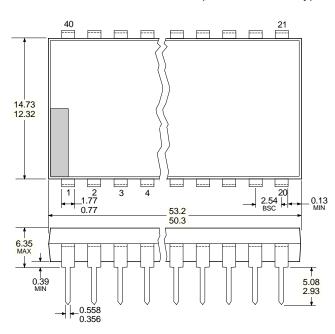
## A6818EA, A6811KA, & A6811SA

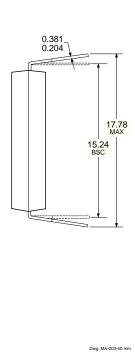
Dimensions in Inches (controlling dimensions)





# Dimensions in Millimeters (for reference only)





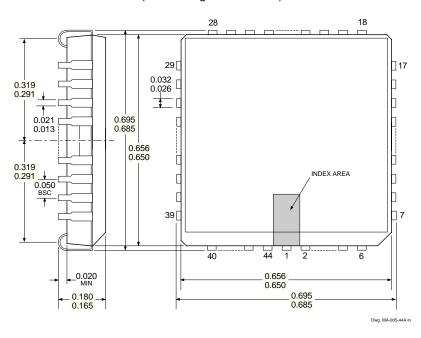
NOTES: 1. Exact body and lead configuration at vendor's option within limits shown.

- 2. Lead spacing tolerance is non-cumulative.
- 3. Lead thickness is measured at seating plane or below.

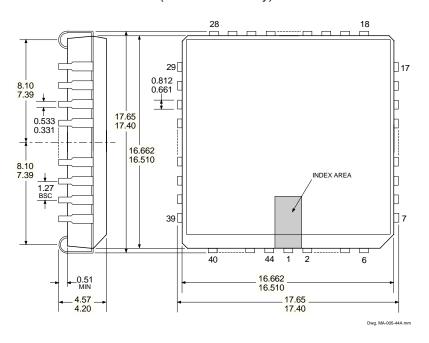


## A6818EEP, A6818KEP, & A6818SEP

Dimensions in Inches (controlling dimensions)



# Dimensions in Millimeters (for reference only)



NOTES: 1. Exact body and lead configuration at vendor's option within limits shown.

2. Lead spacing tolerance is non-cumulative.

# BiMOS II (Series 5800) & DABiC IV (Series 6800) INTELLIGENT POWER INTERFACE DRIVERS SELECTION GUIDE

Function	Output F	Ratings *	Part Number †								
SERIAL-INPUT LATCHED DRIVERS											
8-Bit (saturated drivers)	-120 mA	50 V‡	5895								
8-Bit	350 mA	50 V	5821								
8-Bit	350 mA	80 V	5822								
8-Bit	350 mA	50 V‡	5841								
8-Bit	350 mA	80 V‡	5842								
8-Bit (constant-current LED driver)	75 mA	17 V	6275								
9-Bit	1.6 A	50 V	5829								
10-Bit (active pull-downs)	-25 mA	60 V	5810-F and 6809/10								
12-Bit (active pull-downs)	-25 mA	60 V	5811 and 6811								
16-Bit (constant-current LED driver)	75 mA	17 V	6276								
20-Bit (active pull-downs)	-25 mA	60 V	5812-F and 6812								
32-Bit (active pull-downs)	-25 mA	60 V	5818-F and 6818								
32-Bit	100 mA	30 V	5833								
32-Bit (saturated drivers)	100 mA	40 V	5832								
PARAL	LEL-INPUT LATCHED D	RIVERS									
4-Bit	350 mA	50 V‡	5800								
8-Bit	-25 mA	60 V	5815								
8-Bit	350 mA	50 V‡	5801								
SPECIAL-PURPOSE FUNCTIONS											
Unipolar Stepper Motor Translator/Driver	1.25 A	50 V‡	5804								
Addressable 28-Line Decoder/Driver	450 mA	30 V	6817								

<sup>\*</sup> Current is maximum specified test condition, voltage is maximum rating. See specification for sustaining voltage limits. Negative current is defined as coming out of (sourcing) the output.

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<sup>†</sup> Complete part number includes additional characters to indicate operating temperature range and package style.

<sup>‡</sup> Internal transient-suppression diodes included for inductive-load protection.